Radiation-induced Soft Errors: A Chip-level Modeling Perspective

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Contents

1 Introduction 1
  1.1 SER Fundamentals 2
  1.2 Particle-induced Soft Error Upset Modes 4
  1.3 The Unit of SER 8
  1.4 System-level Error Types 8

2 The Physics of Soft Errors in a Terrestrial Radiation Environment 11
  2.1 Charge Generation and Collection Process 11
  2.2 The Terrestrial Radiation Environment 13

3 SER Trends 25
  3.1 Nominal SBU SER Trends 25
  3.2 MCU Trends 30
  3.3 Combinational Logic SER Trends 33
  3.4 Redundancy-hardened Device SER Trends 36

4 SER Modeling Approaches 39
  4.1 Accuracy Considerations 39
  4.2 Nominal SBU Modeling 42
  4.3 Timing Vulnerability Factor (TVF) Modeling 61
  4.4 SER Simulations of Static Combinational Logic 67
### 4.5 Architectural Vulnerability Factors (AVF) Modeling

4.6 A Circuit-level Simulation Strategy of Radhard Devices that Utilize Redundancy

4.7 Modeling of MBU in Memory Arrays

4.8 Chip-level SER Rollup: Putting it all together

### Acknowledgments

### A Appendices

A.1 Appendix 1 — Selected Acronyms

A.2 Appendix 2 — Selected Online Resources

A.3 Appendix 3 — Alternative SEU Models

A.4 Appendix 4 — A simple SER Compact Model

A.5 Appendix 5 — A Compact Model that accounts for Charge Sharing

### References